



# EMI TEST REPORT

Test Report No. : 4786001221H-B

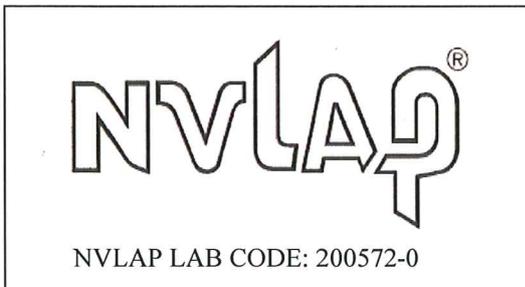
**Applicant** : SHARP CORPORATION  
**Type of Equipment** : Cellular Phone  
**Model No.** : 202SH  
**FCC ID** : APYHRO00182  
**Test regulation** : FCC Part 15 Subpart B: 2012 Class B  
**Test Result** : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the limits of the above regulation.
4. The test results in this test report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

**Date of test:** November 26 and 27, 2012

**Representative test engineer:**   
Yutaka Yoshida  
Engineer of WiSE Japan,  
UL Verification Service

**Approved by:**   
Takahiro Hatakeda  
Leader of WiSE Japan,  
UL Verification Service



This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.  
\*As for the range of Accreditation in NVLAP, you may refer to the WEB address,  
<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

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## **SECTION 1: Customer information**

Company Name : SHARP CORPORATION  
Address : 2-13-1 Iida, Hachihonmatsu, Higashi-Hiroshima City, Hiroshima,  
739-0192 Japan  
Telephone Number : +81-82-420-1827  
Facsimile Number : +81-82-420-1572  
Contact Person : Hiroyuki Uwatoko

## **SECTION 2: Equipment Under Test (E.U.T.)**

### **2.1 Identification of E.U.T.**

Type of Equipment : Cellular Phone  
Model No. : 202SH  
Serial No. : Refer to Section 4, Clause 4.2  
Receipt Date of Sample : November 22, 2012  
Country of Mass-production : Japan  
Condition of EUT : Production prototype  
(Not for Sale: This sample is equivalent to mass-produced items.)  
Modification of EUT : No Modification by the test lab

### **2.2 Product description**

Feature of EUT : 202SH is Dual-band (FDD I/FDD VIII) WCDMA & Tri-band  
(900/1800/1900) GSM Dual mode Cellular Phone.  
The EUT has the function that Bluetooth wireless technology interface  
for establishing contact and transmitting data with certain device.  
Clock frequency(ies) in the system : CPU: 208MHz (Max)  
Source oscillation: 26MHz

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**UL Japan, Inc.**

**Head Office EMC Lab.**

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Telephone : +81 596 24 8116

Facsimile : +81 596 24 8124

## SECTION 3: Test specification, procedures & results

### 3.1 Test specification

Test Specification : FCC Part 15 Subpart B: 2012, final revised on August 13, 2012 and effective September 12, 2012

Title : FCC 47CFR Part15 Radio Frequency Device  
Subpart B Unintentional Radiators

### 3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2009 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 14.3dB 0.17115MHz, L [AV] 13.6dB 0.17114MHz, N	Complied
Radiated emission	ANSI C63.4: 2009 8. Radiated emission measurements	Class B	N/A	8.5dB 447.358MHz, Horizontal, QP	Complied

\*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

### 3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

### 3.4 Uncertainty

#### EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi- anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.5dB
No.2	3.6dB
No.3	3.6dB
No.4	3.6dB

Test room (semi- anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	4.3dB	5.0dB	5.1dB	4.9dB	5.8dB	4.4dB	4.3dB
No.2	4.3dB	5.2dB	5.1dB	5.0dB	5.7dB	4.3dB	4.2dB
No.3	4.6dB	5.0dB	5.1dB	5.0dB	5.7dB	4.5dB	4.2dB
No.4	4.8dB	5.2dB	5.0dB	5.0dB	5.7dB	5.2dB	4.2dB

\*3m/1m/0.5m = Measurement distance

#### Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

#### Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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### 3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. \*NVLAP Lab. code: 200572-0  
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN  
Telephone : +81 596 24 8116 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

\* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

### 3.6 Data of EMI, Test instruments, and Test set up

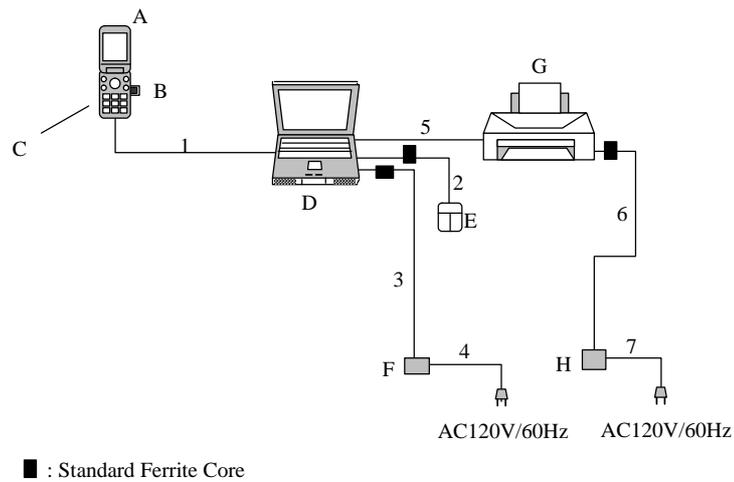
Refer to APPENDIX.

## **SECTION 4: Operation of E.U.T. during testing**

### **4.1 Operating modes**

The mode(s) : 1) USB Data Com Mode  
The USB data is communicated between EUT and Personal computer (Pair of EUT).  
2) Standby Mode  
Standby state for USB communication.

### **4.2 Configuration and peripherals**



\*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

**Description of EUT and Support equipment**

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Cellular Phone	202SH	004401/11/454421/2	Sharp Corporation	EUT
B	microSD Memory Card	SD-MD008GA	None	TOSHIBA	-
C	Lithium-Ion Battery	SHBCU1	VDA	Sharp Corporation	EUT
D	Personal Computer	PP11L	CN-0D4571-48643-55V-1651	Dell	-
E	Mouse	M-BE55	LZE21450232	Logitech	-
F	AC Adapter(PC)	PA-1650-05D2	CN-0F7970-71615-561-14A1	Dell	-
G	Printer	895Cxi	SG8BL1W16V	Hewlett Packard	-
H	AC Adapter(Printer)	C4557-60004	C8K28B	Hewlett Packard	-

**List of cables used**

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	0.80	Shielded	Shielded	-
2	Mouse Cable	0.72	Unshielded	Unshielded	-
3	AC Adaptor Cable (PC)	1.76	Unshielded	Unshielded	-
4	AC Power Cable (PC)	0.85	Unshielded	Unshielded	-
5	Parallel Cable	1.65	Shielded	Shielded	-
6	AC Adapter Cable (printer)	2.00	Unshielded	Unshielded	-
7	AC Power Cable (printer)	1.75	Unshielded	Unshielded	-

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## **SECTION 5: Conducted Emission**

### **5.1 Operating environment**

Test place : No. 4 semi anechoic chamber.  
Temperature : See data  
Humidity : See data

### **5.2 Test configuration**

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment. Photographs of the set up are shown in Appendix 1.

Frequency range : 0.15 MHz-30MHz  
EUT position : Table top  
EUT operation mode : See Clause 4.1

### **5.3 Test procedure**

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and Average  
IF Bandwidth : 9 kHz

### **5.4 Test result**

Summary of the test results: Pass

Date: November 27, 2012                      Test engineer: Keisuke Kawamura

## **SECTION 6: Radiated Emission**

### **6.1 Operating environment**

Test place : No. 1 semi anechoic chamber  
Temperature : See data  
Humidity : See data

### **6.2 Test configuration**

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the edge of the tabletop.  
Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.  
Photographs of the set up are shown in Appendix 1.

### **6.3 Test conditions**

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)  
1GHz-2GHz (Horn antenna)  
Test distance : 3m  
EUT position : Table top  
EUT operation mode : See Clause 4.1

### **6.4 Test procedure**

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.  
The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.  
The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer *1)
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 3MHz AV *2): RBW:1MHz/VBW:10Hz

\*1) The Spectrum Analyzer was used in 3dB resolution bandwidth.

\*2) When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at representative X-axis since no difference was found among each position.

### **6.5 Test result**

Summary of the test results: Pass

Date: November 26, 2012      Test engineer: Keisuke Kawamura

**APPENDIX 1: Data of EMI test**

**Conducted Emission**

**DATA OF CONDUCTED EMISSION TEST**

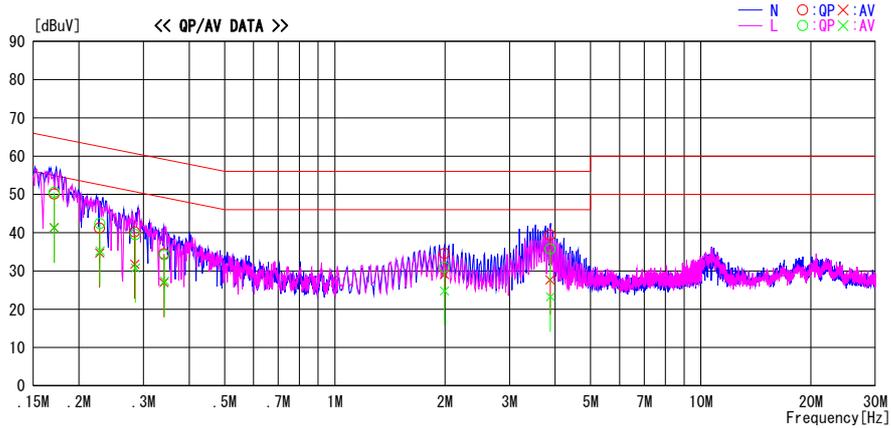
UL Japan, Inc. Head Office EMC Lab. No.4 Semi Anechoic Chamber  
Date : 2012/11/27

Report No. : 4786001221H

Temp./Humi. : 20deg. C / 31% RH  
Engineer : Keisuke Kawamura

Mode / Remarks : USB Data Com mode

LIMIT : FCC15.107(a) QP ClassB  
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.17114	36.8	28.0	13.3	50.1	41.3	64.9	54.9	14.8	13.6	N	
0.22765	27.9	21.4	13.3	41.2	34.7	62.5	52.5	21.3	17.8	N	
0.28398	26.9	18.5	13.3	40.2	31.8	60.7	50.7	20.5	18.9	N	
0.34152	21.1	13.6	13.4	34.5	27.0	59.2	49.2	24.7	22.2	N	
1.99384	21.1	15.6	13.5	34.6	29.1	56.0	46.0	21.4	16.9	N	
3.87559	25.7	14.0	13.7	39.4	27.7	56.0	46.0	16.6	18.3	N	
0.17115	37.3	27.9	13.3	50.6	41.2	64.9	54.9	14.3	13.7	L	
0.22811	29.1	21.9	13.3	42.4	35.2	62.5	52.5	20.1	17.3	L	
0.28524	26.2	17.5	13.3	39.5	30.8	60.7	50.7	21.2	19.9	L	
0.34232	20.8	13.9	13.4	34.2	27.3	59.1	49.1	24.9	21.8	L	
1.99157	17.4	11.3	13.5	30.9	24.8	56.0	46.0	25.1	21.2	L	
3.87919	22.0	9.5	13.7	35.7	23.2	56.0	46.0	20.3	22.8	L	

CHART:WITH FACTOR, Peak hold data. CALCULATION:RESULT=READING+C.F(LISN LOSS + CABLE LOSS)  
Except for the above table : adequate margin data below the limits.

\*The limit is rounded down to one decimal place.  
\*The test result is rounded off to one or two decimal places, so some differences might be observed.

## Conducted Emission

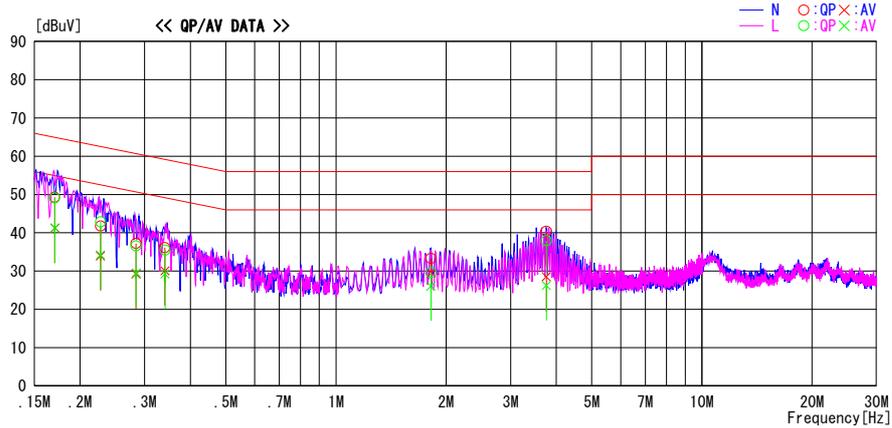
### DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.4 Semi Anechoic Chamber  
 Date : 2012/11/27

Report No. : 4786001221H  
 Temp./Humi. : 20deg. C / 31% RH  
 Engineer : Keisuke Kawamura

Mode / Remarks : Standby mode

LIMIT : FCC15.107(a) QP ClassB  
 FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.17051	36.0	27.9	13.3	49.3	41.2	64.9	54.9	15.6	13.7	N	
0.22749	28.4	20.7	13.3	41.7	34.0	62.5	52.5	20.8	18.5	N	
0.28426	23.9	15.9	13.3	37.2	29.2	60.7	50.7	23.5	21.5	N	
0.34112	22.7	16.7	13.4	36.1	30.1	59.2	49.2	23.1	19.1	N	
1.82034	19.8	16.0	13.5	33.3	29.5	56.0	46.0	22.7	16.5	N	
3.75848	26.7	14.8	13.7	40.4	28.5	56.0	46.0	15.6	17.5	N	
0.17054	35.8	27.9	13.3	49.1	41.2	64.9	54.9	15.8	13.7	L	
0.22743	29.5	20.9	13.3	42.8	34.2	62.5	52.5	19.7	18.3	L	
0.28462	23.3	16.2	13.3	36.6	29.5	60.7	50.7	24.1	21.2	L	
0.34126	22.1	15.8	13.4	35.5	29.2	59.2	49.2	23.7	20.0	L	
1.81844	16.1	12.6	13.5	29.6	26.1	56.0	46.0	26.4	19.9	L	
3.75848	24.2	12.5	13.7	37.9	26.2	56.0	46.0	18.1	19.8	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT=READING+C.F (LISN LOSS + CABLE LOSS)  
 Except for the above table : adequate margin data below the limits.

\*The limit is rounded down to one decimal place.  
 \*The test result is rounded off to one or two decimal places, so some differences might be observed.

## Radiated Emission (Below 1GHz)

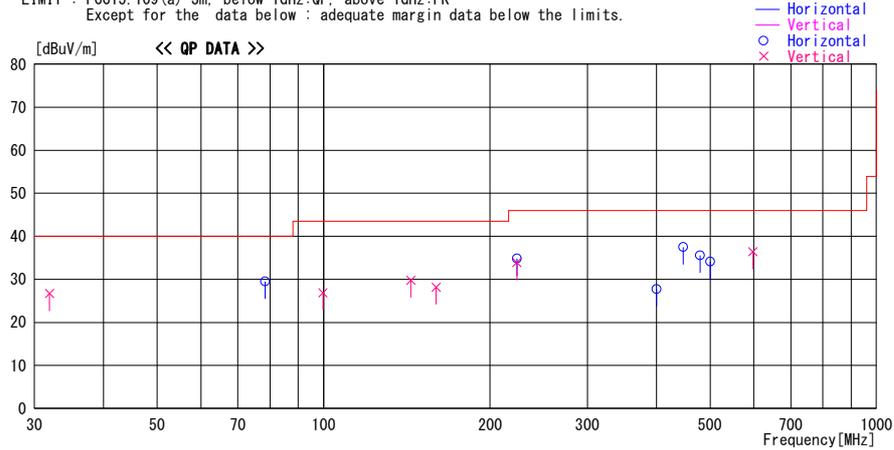
### DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber  
Date : 2012/11/26

Report No. : 4786001221H  
Temp./Humi. : 18deg. C / 42% RH  
Engineer : Keisuke Kawamura

Mode / Remarks : USB Data Com mode

LIMIT : FCC15.109 (a) 3m, below 1GHz:QP, above 1GHz:PK  
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
31.958	41.0	QP	17.2	-31.5	26.7	23	100	Vert.	40.0	13.3	
78.416	53.7	QP	6.5	-30.7	29.5	131	266	Hori.	40.0	10.5	
99.761	47.6	QP	9.8	-30.5	26.9	248	100	Vert.	43.5	16.6	
143.792	45.1	QP	14.6	-29.9	29.8	245	100	Vert.	43.5	13.7	
159.769	42.8	QP	15.2	-29.8	28.2	139	100	Vert.	43.5	15.3	
223.679	45.8	QP	17.1	-29.0	33.9	346	100	Vert.	46.0	12.1	
223.679	46.7	QP	17.1	-29.0	34.8	173	158	Hori.	46.0	11.2	
399.998	37.3	QP	17.6	-27.2	27.7	359	100	Hori.	46.0	18.3	
447.358	46.4	QP	17.9	-26.8	37.5	215	100	Hori.	46.0	8.5	
479.315	44.0	QP	18.1	-26.5	35.6	302	100	Hori.	46.0	10.4	
500.363	42.2	QP	18.2	-26.3	34.1	4	100	Hori.	46.0	11.9	
597.551	42.6	QP	19.4	-25.6	36.4	355	118	Vert.	46.0	9.6	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN  
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

\*The limit is rounded down to one decimal place.  
\*The test result is rounded off to one or two decimal places, so some differences might be observed.

## Radiated Emission (Below 1GHz)

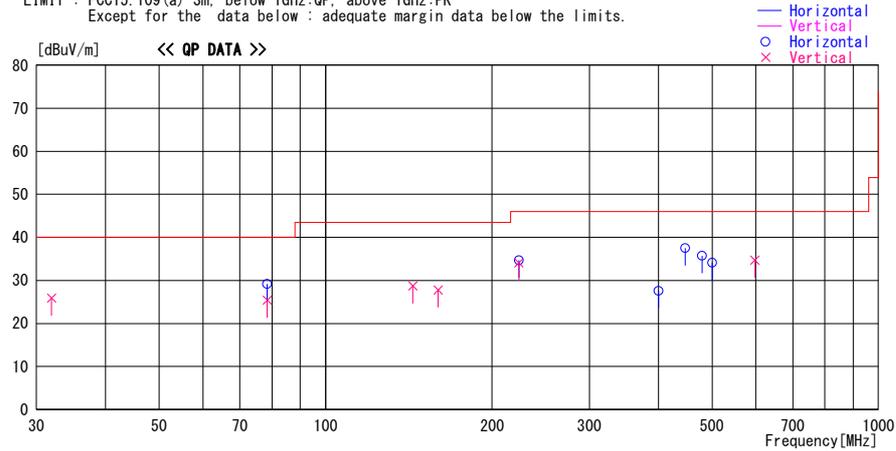
### DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber  
Date : 2012/11/26

Report No. : 4786001221H  
Temp./Humi. : 18deg. C / 42% RH  
Engineer : Keisuke Kawamura

Mode / Remarks : Standby mode

LIMIT : FCC15.109 (a) 3m, below 1GHz:QP, above 1GHz:PK  
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level	Angle	Height	Polar.	Limit	Margin	Comment
			Factor	Gain							
31.958	40.2	QP	17.2	-31.5	25.9	22	100	Vert.	40.0	14.1	
78.416	53.4	QP	6.5	-30.7	29.2	132	265	Hori.	40.0	10.8	
78.416	49.6	QP	6.5	-30.7	25.4	218	100	Vert.	40.0	14.6	
143.792	44.0	QP	14.6	-29.9	28.7	222	100	Vert.	43.5	14.8	
159.769	42.4	QP	15.2	-29.8	27.8	132	100	Vert.	43.5	15.7	
223.679	46.0	QP	17.1	-29.0	34.1	350	100	Vert.	46.0	11.9	
223.679	46.6	QP	17.1	-29.0	34.7	173	157	Hori.	46.0	11.3	
399.998	37.2	QP	17.6	-27.2	27.6	359	100	Hori.	46.0	18.4	
447.358	46.4	QP	17.9	-26.8	37.5	216	100	Hori.	46.0	8.5	
479.315	44.1	QP	18.1	-26.5	35.7	302	100	Hori.	46.0	10.3	
500.363	42.2	QP	18.2	-26.3	34.1	6	100	Hori.	46.0	11.9	
597.551	40.9	QP	19.4	-25.6	34.7	359	113	Vert.	46.0	11.3	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN  
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

\*The limit is rounded down to one decimal place.  
\*The test result is rounded off to one or two decimal places, so some differences might be observed.

**Radiated Emission**  
**(Above 1GHz)**

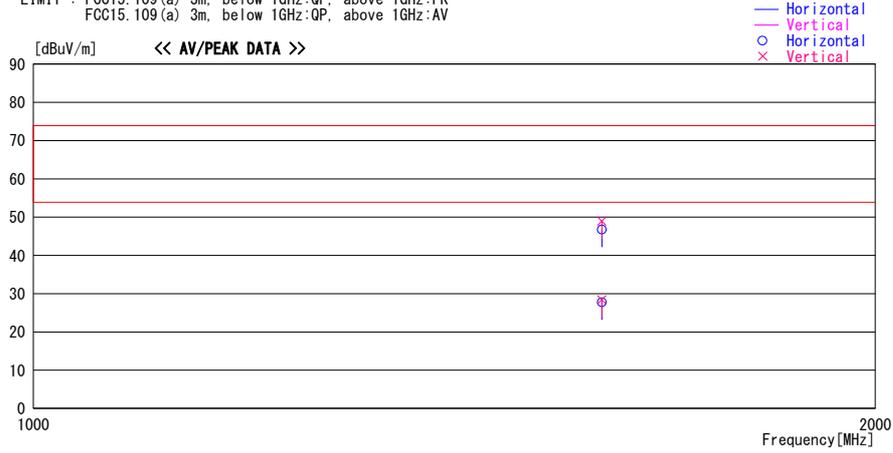
**DATA OF RADIATED EMISSION TEST**

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber  
Date : 2012/11/26

Report No. : 4786001221H  
Temp./Humi. : 18deg. C / 42% RH  
Engineer : Keisuke Kawamura

Mode / Remarks : USB Data Com mode

LIMIT : FCC15.109 (a) 3m, below 1GHz:QP, above 1GHz:PK  
FCC15.109 (a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level	Angle	Height	Polar.	Limit	Margin	Comment
			Factor [dB/m]	Gain [dB]							
1596.491	37.2	AV	25.8	-34.6	28.4	49	100	Vert.	53.9	25.5	
1596.491	57.8	PK	25.8	-34.6	49.0	49	100	Vert.	73.9	24.9	
1596.491	55.6	PK	25.8	-34.6	46.8	237	100	Hori.	73.9	27.1	
1596.491	36.5	AV	25.8	-34.6	27.7	237	100	Hori.	53.9	26.2	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz--:HORN  
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

\*The limit is rounded down to one decimal place.  
\*The test result is rounded off to one or two decimal places, so some differences might be observed.

**Radiated Emission**  
**(Above 1GHz)**

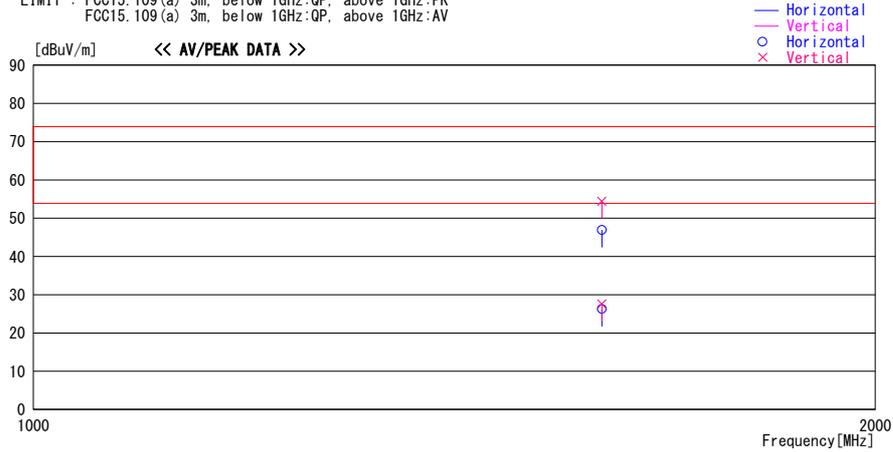
**DATA OF RADIATED EMISSION TEST**

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber  
Date : 2012/11/26

Report No. : 4786001221H  
Temp./Humi. : 18deg. C / 42% RH  
Engineer : Keisuke Kawamura

Mode / Remarks : Standby mode

LIMIT : FCC15.109 (a) 3m, below 1GHz:QP, above 1GHz:PK  
FCC15.109 (a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss& Gain	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	[dB]							
1596.491	36.4	AV	25.8	-34.6	27.6	49	100	Vert.	53.9	26.3	
1596.491	63.2	PK	25.8	-34.6	54.4	49	100	Vert.	73.9	19.5	
1596.491	55.8	PK	25.8	-34.6	47.0	237	100	Hori.	73.9	27.0	
1596.491	35.1	AV	25.8	-34.6	26.3	237	100	Hori.	53.9	27.6	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz:-HORN  
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

\*The limit is rounded down to one decimal place.  
\*The test result is rounded off to one or two decimal places, so some differences might be observed.

## **APPENDIX 2: Test instruments**

### **EMI test equipment**

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE	2012/08/01 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE	2012/02/08 * 12
MJM-01	Measure	KDS	ES19-55	-	RE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Reseiver	Rohde & Schwarz	ESU26	100412	RE	2012/06/14 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2011/11/23 * 12
KLA-04	Logperiodic Antenna	Schwarzbeck	USLP9143	361	RE	2011/11/23 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2012/11/06 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent/TSJ	-	-	RE	2012/09/13 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2012/02/20 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2012/06/27 * 12
MCC-142	Microwave Cable	Junkosha	MWX221	1203S213(1m) / 1204S063(5m)	RE	2012/04/23 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2012/02/28 * 12
MAEC-04	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	CE	2012/02/29 * 12
MOS-13	Thermo-Hygrometer	Custom	CTH-180	-	CE	2012/02/06 * 12
MJM-09	Measure	KDS	E19-55	-	CE	-
MSA-05	Spectrum Analyzer	Advantest	R3273	160400285	CE	2012/11/21 * 12
MTR-07	Test Receiver	Rohde & Schwarz	ESCI	100635	CE	2012/04/05 * 12
MLS-06	LISN(AMN)	Schwarzbeck	NSLK8127	8127363	CE(EUT)	2012/02/06 * 12
MLS-07	LISN(AMN)	Schwarzbeck	NSLK8127	8127364	CE(AE)	2012/02/09 * 12
MTA-30	Terminator	TME	CT-01	-	CE	2012/01/11 * 12
MAT-67	Attenuator	JFW Industries, Inc.	50FP-013H2 N	-	CE	2012/01/28 * 12
MCC-113	Coaxial cable	Fujikura/Suhner/TSJ	5D-2W(10m)/SFM141(5m)/421-010(1m)/sucoform141-PE(1m)/RFM-E121(Switcher)	-/04178	CE	2012/07/12 * 12

**The expiration date of the calibration is the end of the expired month.**

**All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.**

**As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.**

**Test Item:**

**CE: Conducted emission**

**RE: Radiated emission**

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